

MAR 16 2005

RESPONSE UNDER 37 CFR 1.116
EXPEDITED PROCEDURE
EXAMINING GROUP 2829PATENT APPLICATION
Docket No.: 8750-017
Client Ref. No.: SPX200110-0010US

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of: Sang-Eun LEE and Jae-Sung HAN

Serial No.: 10/068,152 Examiner: Hollington, Jermelle M.

Filed: February 6, 2002 Group Art Unit: 2829

Confirmation No.: 7500

For: METHOD OF IDENTIFYING AND ANALYZING
SEMICONDUCTOR CHIP DEFECTSMail Stop AF
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450AMENDMENT AFTER FINAL REJECTION UNDER 37 CFR 1.116

This paper is responsive to the final Office Action, Paper No. 20041213, mailed on December 16, 2004.

Amendments to the Claims begin on page 2 of this paper.

Remarks/Arguments begin on page 4 of this paper.

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